United States Patent [19]

Shirai

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[54] **MICROMETER**

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[73] Assignee: **Mitutoyo Mfg. Co., Ltd.**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **569,631**

[22] Filed: **Jan. 10, 1984**

[52] **U.S. Cl.** **D10/73**; D10/70

[58] **Field of Search** .... D10/73, 74; 33/164 R, 33/164 B, 164 C, 164 D, 165, 166, 167, 147 E, 170

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[57] **CLAIM**

The ornamental design for a micrometer, as shown.

DESCRIPTION

FIG. **1** is a front and top-right perspective view of a micrometer showing my new design;

FIG. **2** is a re-oriented perspective view of FIG. **1**;

FIG. **3** is a front elevational view thereof;

FIG. **4** is a rear elevational view thereof;

FIG. **5** is a top plan view thereof;

FIG. **6** is a bottom plan view thereof;

FIG. **7** is a left side elevational view thereof; and

FIG. **8** is a right side elevational view thereof.

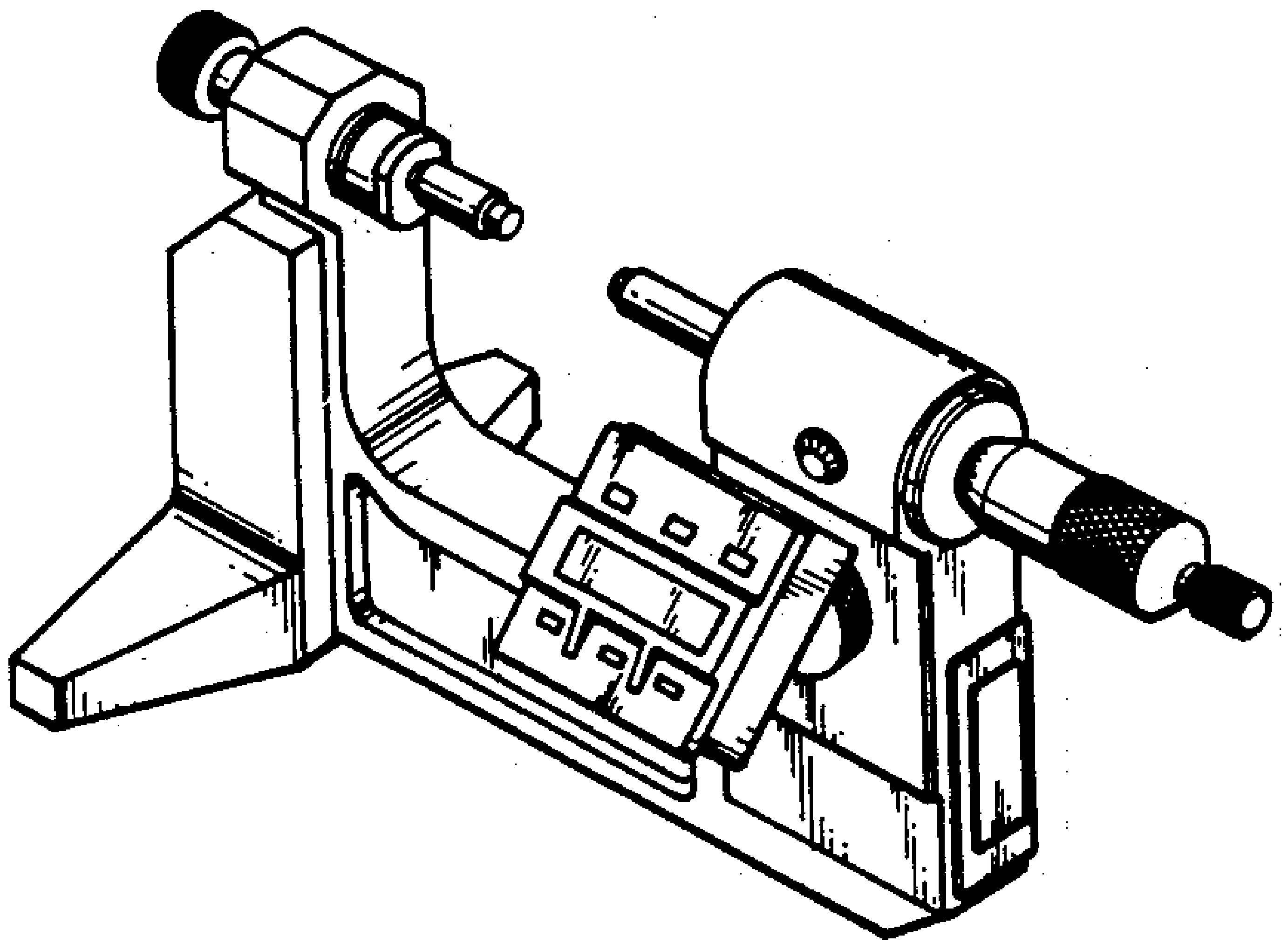

FIG. 1

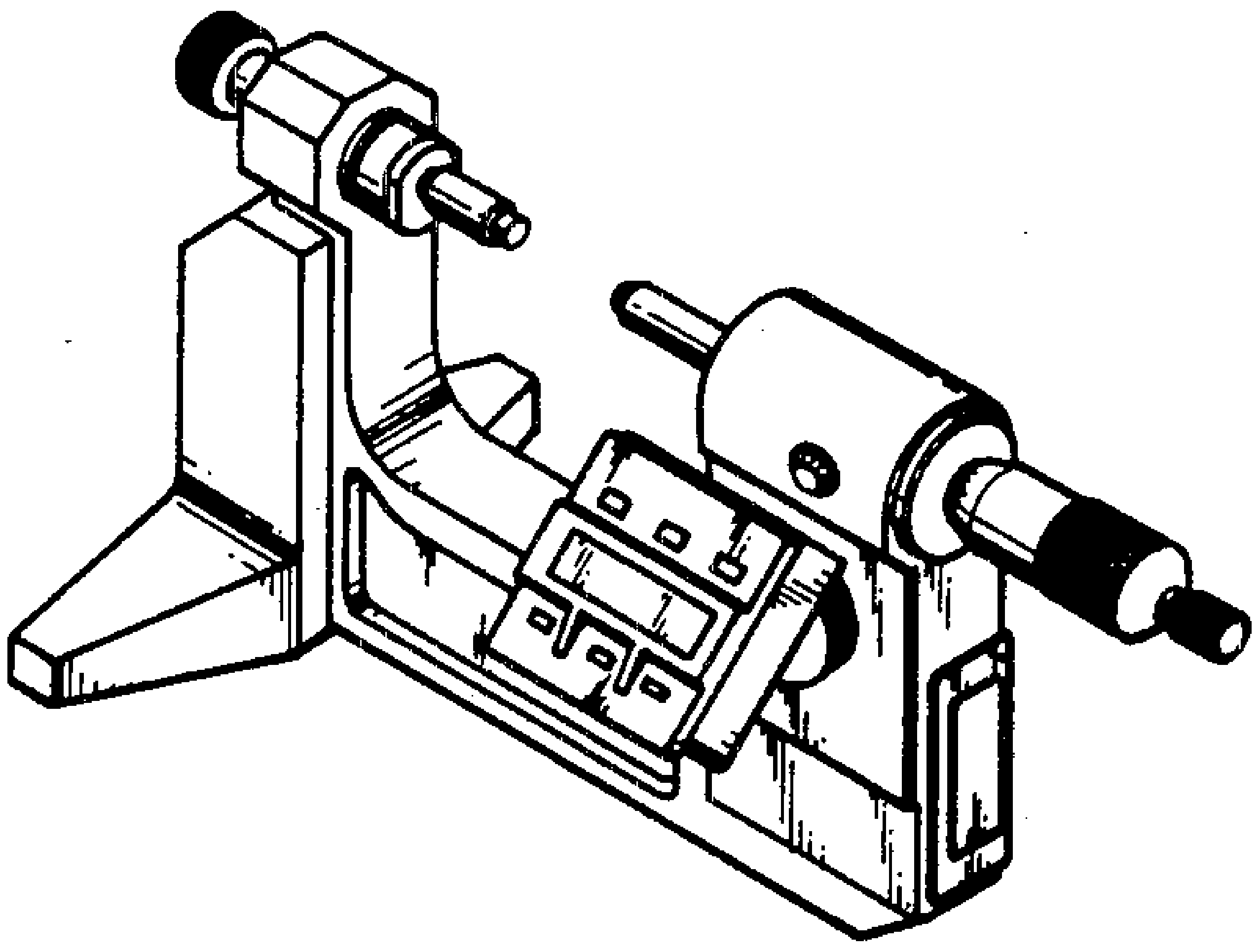

FIG. 2

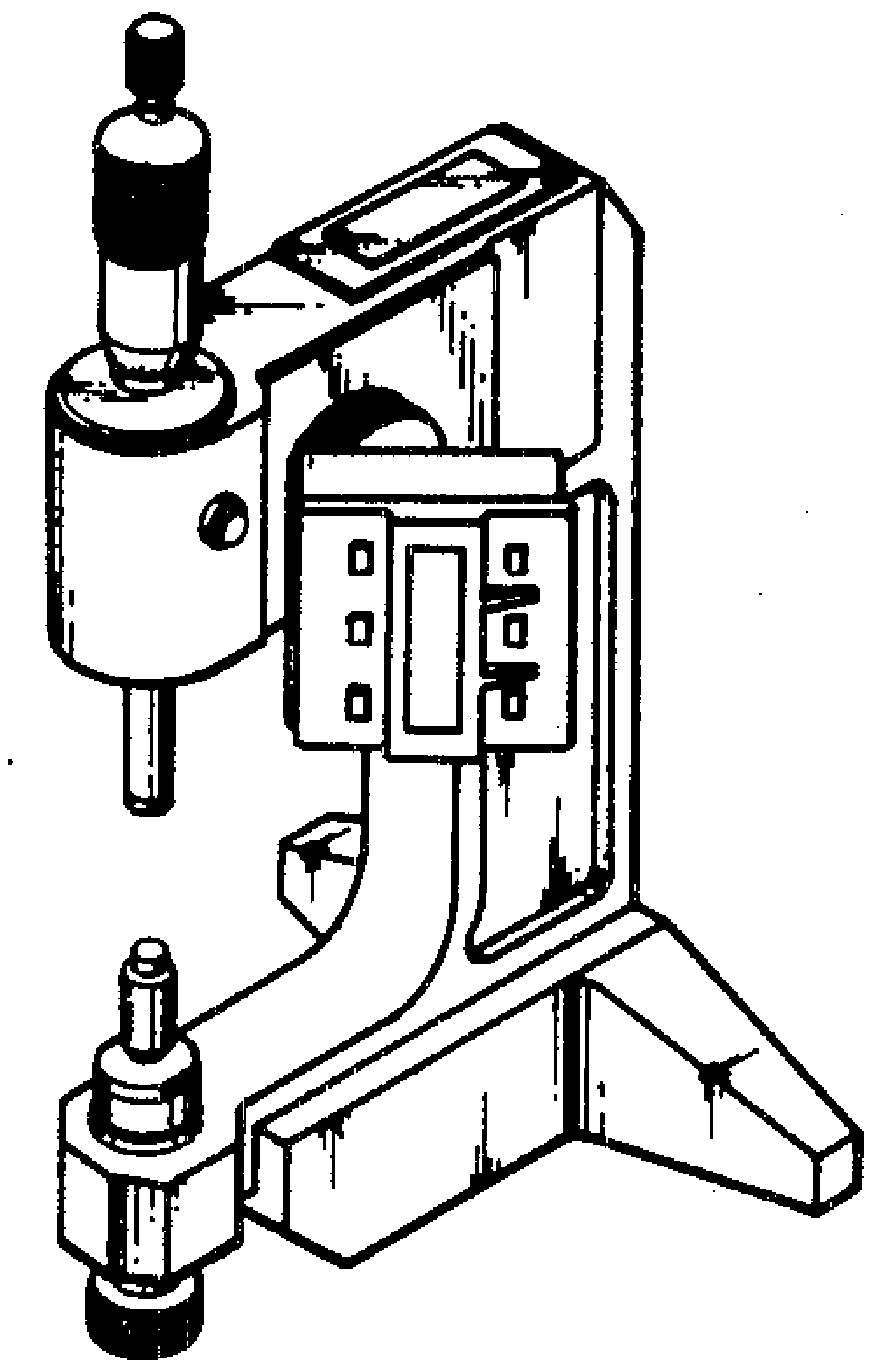

FIG. 3

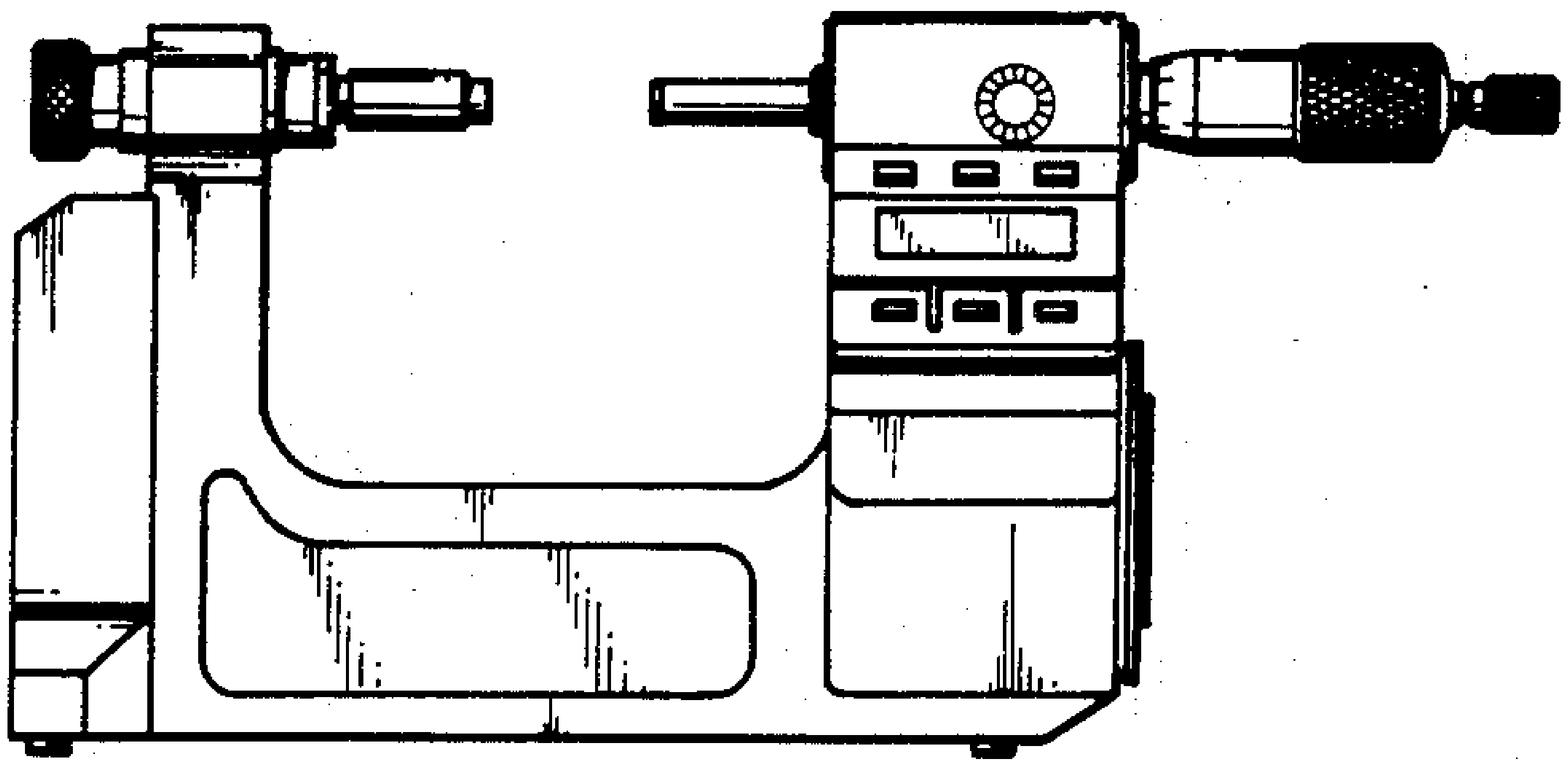

FIG. 4

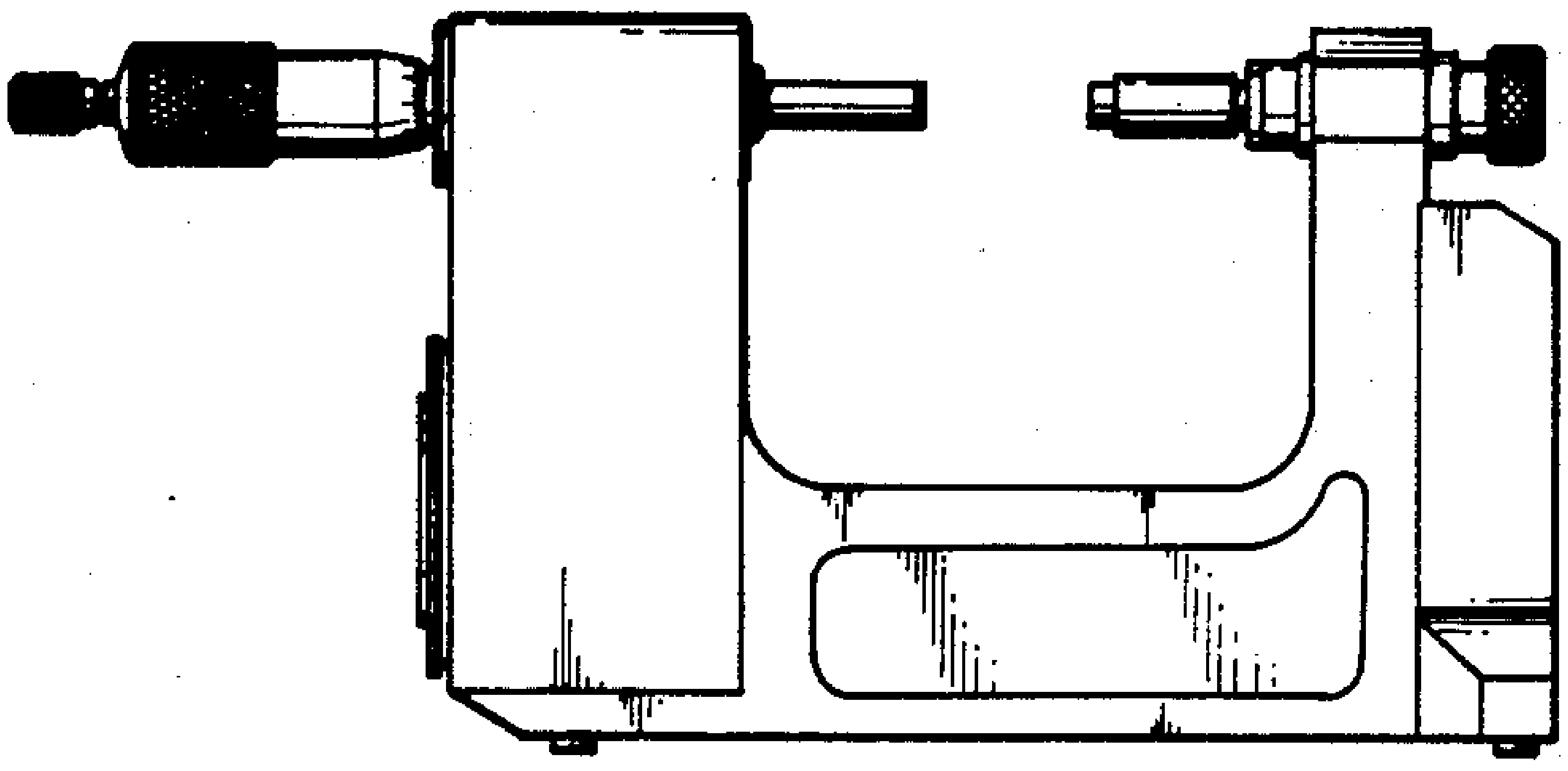

FIG. 5

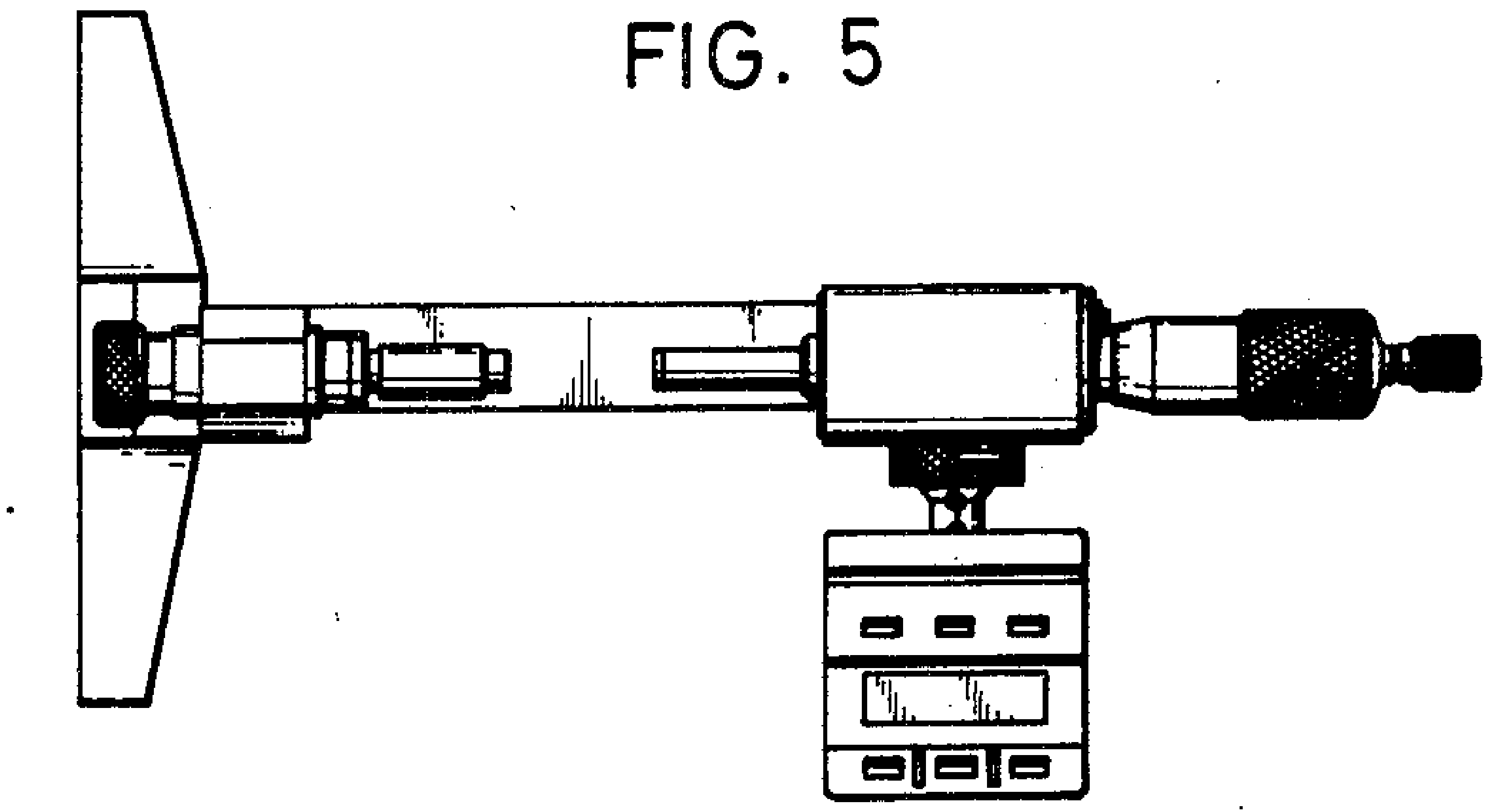

FIG. 6

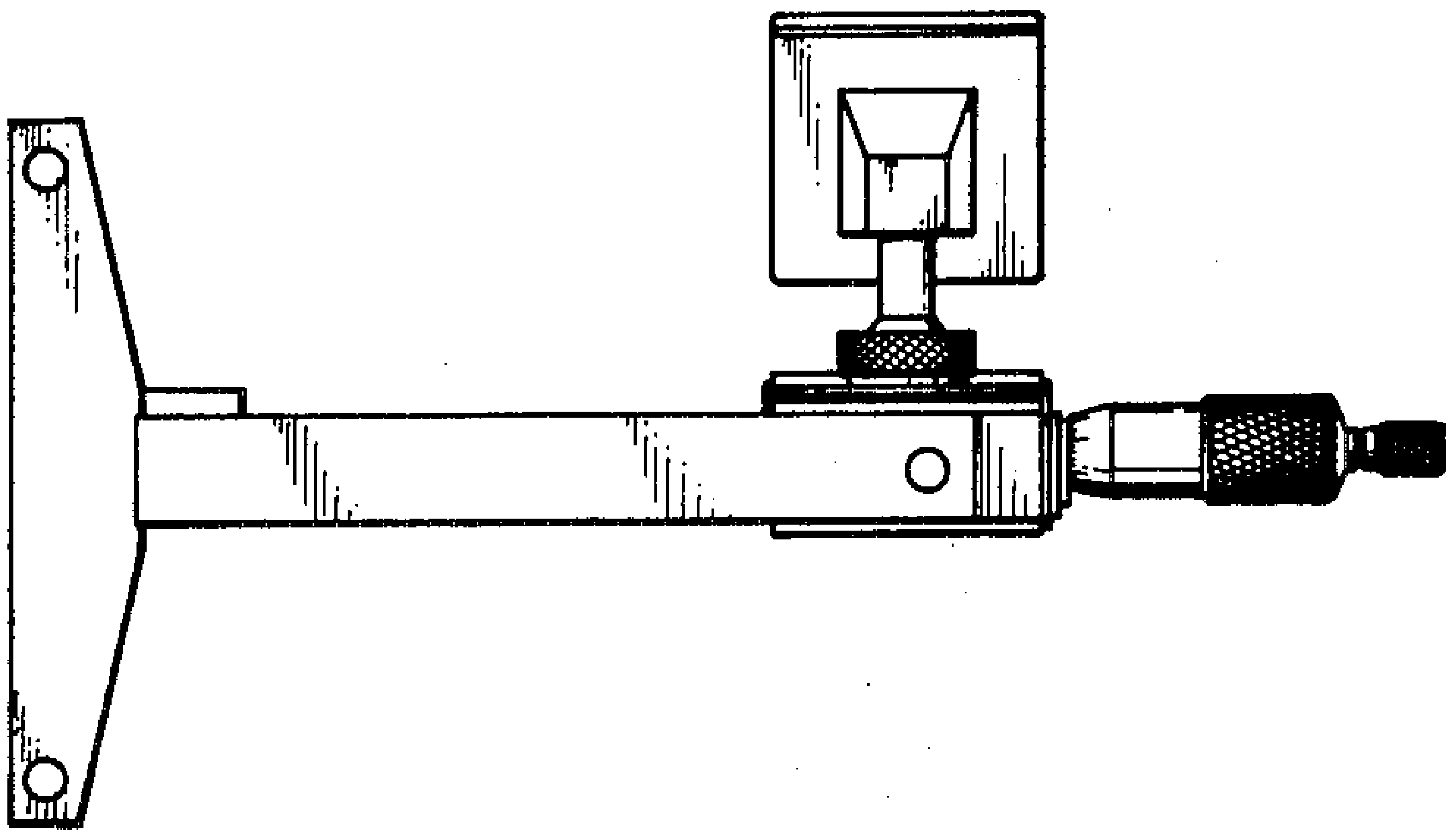

FIG. 7

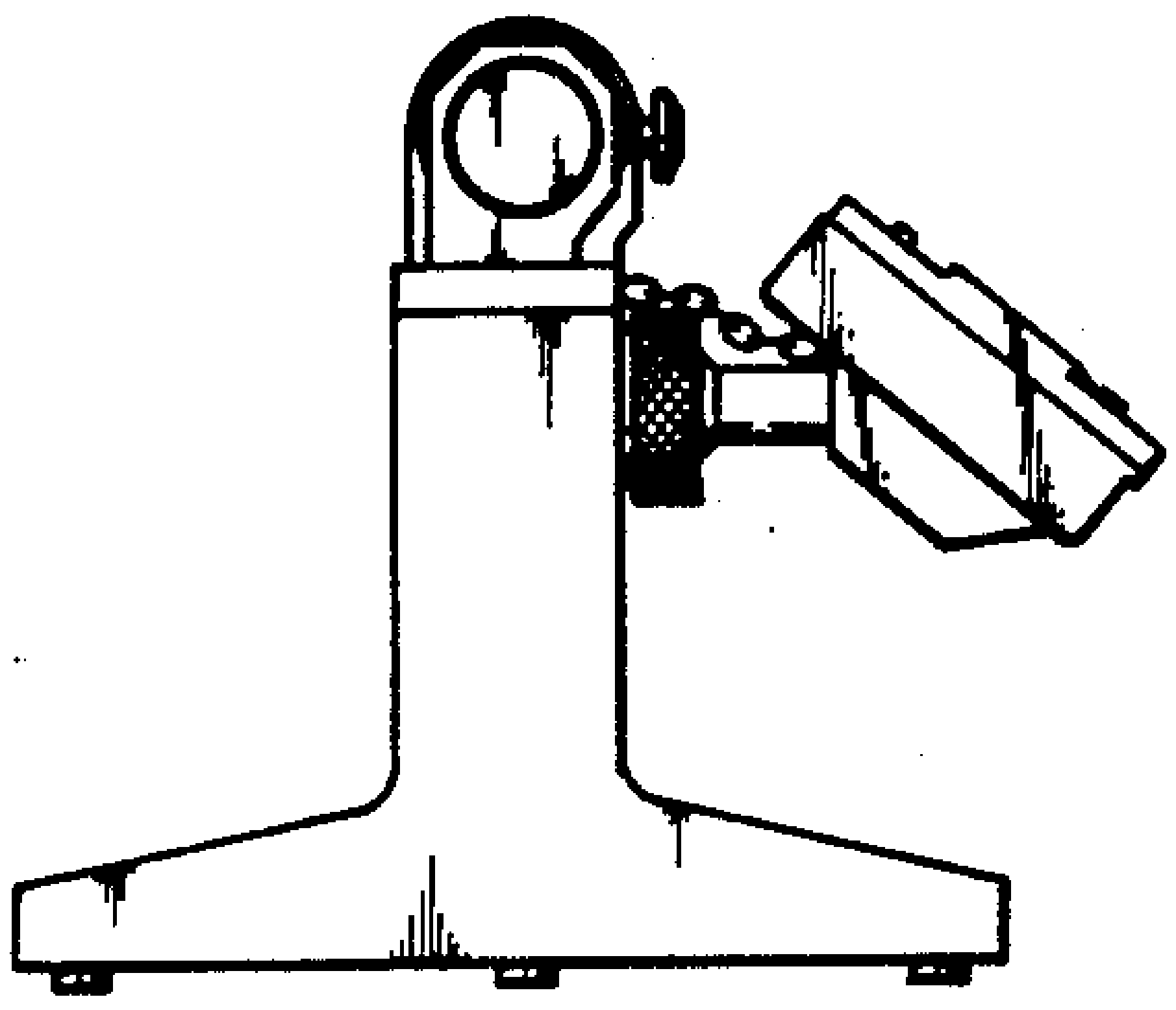

FIG. 8